

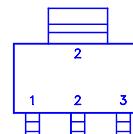
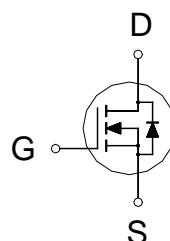
NIKO-SEM
**N-Channel Logic Level Enhancement
Mode Field Effect Transistor**
P3055LLG

SOT-223

Lead-Free

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
25	90m	6A


 1. GATE
 2. DRAIN
 3. SOURCE
ABSOLUTE MAXIMUM RATINGS ($T_C = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current	$T_C = 25^\circ\text{C}$	I_D	6	A
	$T_C = 100^\circ\text{C}$		3.6	
Pulsed Drain Current ¹		I_{DM}	22	
Avalanche Energy	$L = 0.1\text{mH}$	E_{AS}	60	mJ
Repetitive Avalanche Energy ²	$L = 0.05\text{mH}$	E_{AR}	3	
Power Dissipation	$T_C = 25^\circ\text{C}$	P_D	3	W
	$T_C = 100^\circ\text{C}$		1.5	
Operating Junction & Storage Temperature Range		T_j, T_{stg}	-55 to 150	°C
Lead Temperature ($1/16''$ from case for 10 sec.)		T_L	275	

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		12	°C / W
Junction-to-Ambient	$R_{\theta JA}$		42	

¹Pulse width limited by maximum junction temperature.²Duty cycle $\leq 1\%$ **ELECTRICAL CHARACTERISTICS ($T_C = 25^\circ\text{C}$, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	25			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	0.8	1.2	2.5	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0\text{V}, V_{GS} = \pm 20\text{V}$			± 250	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 20\text{V}, V_{GS} = 0\text{V}$			25	μA
		$V_{DS} = 20\text{V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$			250	
On-State Drain Current ¹	$I_{D(\text{ON})}$	$V_{DS} = 10\text{V}, V_{GS} = 10\text{V}$	6			A

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Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 5V, I_D = 3A$	70	120	m
		$V_{GS} = 10V, I_D = 6A$	50	90	
Forward Transconductance ¹	g_f	$V_{DS} = 15V, I_D = 6A$	16		s
DYNAMIC					
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 15V, f = 1MHz$ $V_{DS} = 0.5V_{(BR)DSS}, V_{GS} = 10V, I_D = 3A$ $V_{DS} = 15V, R_L = 1$ $I_D \approx 10A, V_{GS} = 10V, R_{GS} = 2.5$	450		pF
Output Capacitance	C_{oss}		200		
Reverse Transfer Capacitance	C_{rss}		60		
Total Gate Charge ²	Q_g		15		nC
Gate-Source Charge ²	Q_{gs}		2.0		
Gate-Drain Charge ²	Q_{gd}		7.0		
Turn-On Delay Time ²	$t_{d(on)}$		6.0		nS
Rise Time ²	t_r		6.0		
Turn-Off Delay Time ²	$t_{d(off)}$		20		
Fall Time ²	t_f		5.0		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_C = 25^\circ C$)					
Continuous Current	I_S	$I_F = I_S, V_{GS} = 0V$ $I_F = I_S, dI_F/dt = 100A / \mu s$		6	A
Pulsed Current ³	I_{SM}			35	
Forward Voltage ¹	V_{SD}			1.5	
Reverse Recovery Time	t_{rr}		30		
Peak Reverse Recovery Current	$I_{RM(REC)}$		15		
Reverse Recovery Charge	Q_{rr}		0.043		

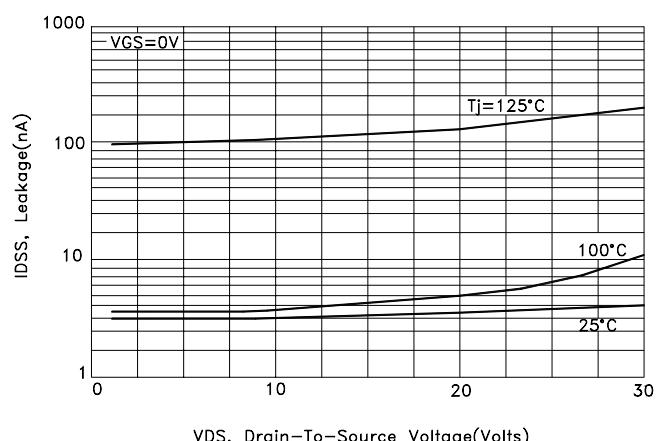
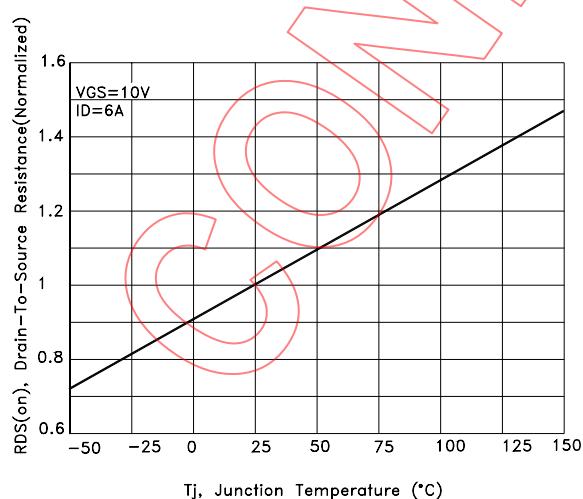
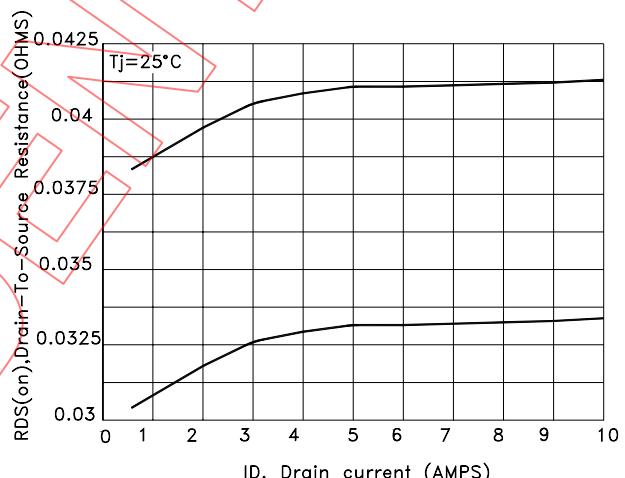
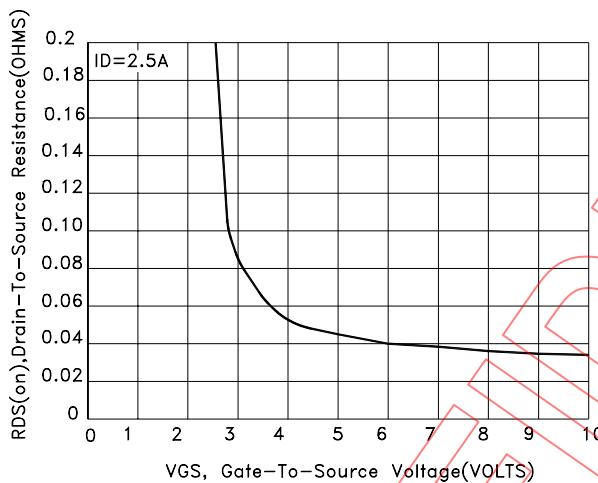
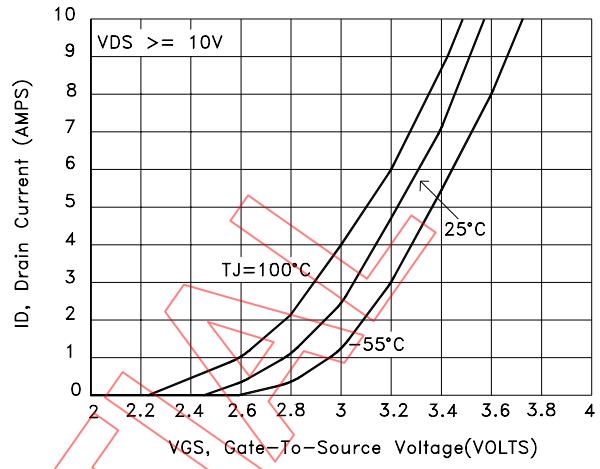
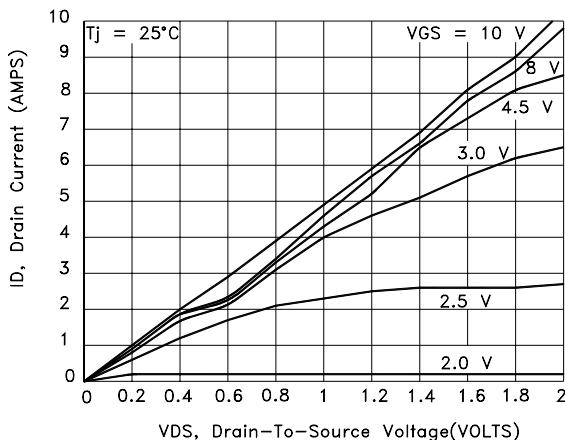
¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.³Pulse width limited by maximum junction temperature.**REMARK: THE PRODUCT MARKED WITH "P3055LLG", DATE CODE or LOT #**

Orders for parts with Lead-Free plating can be placed using the PXXXXXXG parts name.

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SOT-223 MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	0.67	0.7	0.73	H	3.3	3.5	3.7
B	6.7	7	7.3	I	0.63	0.65	0.67
C	2.9	3	3.1	J		0.32	0.4
D	2.27	2.3	2.33	K	0°		10°
E	4.57	4.6	4.63	L	0.03		0.1
F	1.5	1.6	1.7	M			
G	6.3	6.5	6.7	N			

